# FDIRC Simulations and Measurements Update

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### Data Cuts to .dts2 files for Cherenkov Imaging

Table 4.1: List of parameter cuts done to the CRT data set to measure Cherenkov angular resolution.









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### Charge Cut









#### **CRT** Measured Resolution After Dip Corrects





### G4 Charge Cut







#### Monte Carlo Resolution After Dip Corrects



## Why the Wide Secondary Superimposed Gaussian in CRT measurement?

- Possible reason:
  - Electrical cross-talk
  - "fake" hit
    - Due to capacitive loading transitions + AMP oscillations
- I believe it's some kind of random background hits in timing window
  - Electrical
  - Maybe light leak (optical)
- Thus, I redid G4 Monte Carlo with 0.35% chance of a fake hit for every pad per event





# Monte Carlo Resolution After Dip Corrects



### Cherenkov Angular Resolution Comparison <sup>19</sup>

- $\Theta_{\rm C} = \cos^{-1}(ky)$
- Slightly greater sigma for CRT measurement due to mistagging photons + muon tracking error for dip angle
  - Tracking error ~1.1 mrad (quantization error)
- Difference in mean likely due to measurement error in MaPMT slot position



### **End of Slides**